

<b>Notice of References Cited</b>	Application/Control No. 09/550,078	Applicant(s)/Patent Under Reexamination YOSHIO ET AL.	
	Examiner Devona E. Faulk	Art Unit 2615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,618,396	09-2003	Kondo et al.	370/474
*	B	US-6,144,411	11-2000	Kobayashi et al.	348/441
*	C	US-5,802,017	09-1998	Sato et al.	369/2
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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